

BUFFER REGISTERS

8200

N,F,Q PACKAGES

8201 8202

DIGITAL 8000 SERIES TTL/MSI

8203

DESCRIPTION

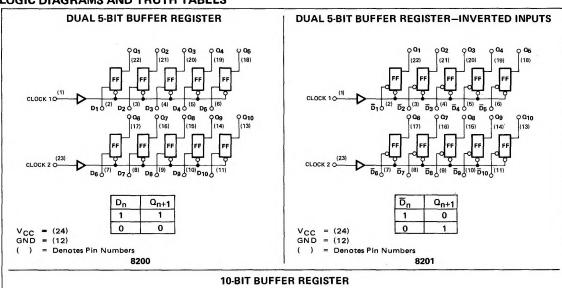
The 8200/8201/8202/8203 MSI Buffer Registers are arrays of ten clocked "D" flip-flops especially suited for parallel-in parallel-out register applications. They are also suitable for general purpose applications as parallel-in serial-out, serial-in parallel-out registers.

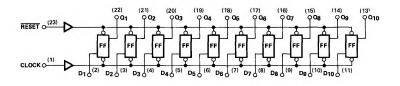
The flip-flops are arranged as dual 5 arrays, (8200 & 8201) and single 10 arrays with reset, (8202 & 8203). The true output of each bit is made available to the user.

The 8200 and 8202 feature true "D" inputs. The logic state presented at these "D" inputs will appear at the Q outputs after a negative transition of the clock.

The 8201 and 8203 feature complementing "D" inputs ("\overline{D}"). The logic state presented at these "\overline{D}" inputs will invert and appear at the Q outputs after a negative going transition of the clock. This complementing input feature ("\overline{D}") permits the use of standard AND-OR-INVERT gates to achieve the AND-OR function without additional gate delays.

LOGIC DIAGRAMS AND TRUTH TABLES





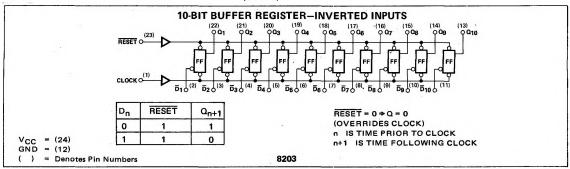
Ì	Dn	RESET	Q _{n+1}			
	1_	1	1			
	0	1	0			

V_{CC} = (24)

GND = (12) () = Denotes Pin Numbers RESET = 0 → Q = 0 (OVERRIDES CLOCK) n IS TIME PRIOR TO CLOCK n+1 IS TIME FOLLOWING CLOCK

8202

LOGIC DIAGRAMS AND TRUTH TABLES (Cont'd)



ELECTRICAL CHARACTERISTICS (Over Recommended Operating Temperature And Voltage)

CHARACTERISTICS		LIMITS			TEST CONDITIONS					
	MIN,	TYP,	MAX.	UNITS	D _n 8200 8202	D _n 8201 8203	CLOCK	RESET 8202 8203	OUTPUTS	NOTES
"1" Output Voltage	2.6	3.5		_v	2.0V	0.8∨	Pulse		– 800μA	6
"0" Output Voltage			0.4	v	0.8V	2.0V	Pulse		9.6mA	7
"0" Input Current										
D _n (8200, 8202)	-0.1		-1.6	mA	0.4V		J		,	
ნე(8201, 8203)	-0.1	1	-1.6	mA		0.4V	ľ			ľ
Clock	-0.1		-1.6	mA			0.4V			
Reset (8202, 8203) '1" Input Current	-0.1		-1.6	mA				0.4V		
D _n (8200, 8202)	Ì		40	μA	4.5V					
Dn (8201, 8203)	[40	μΑ		4.5V				
Clock	ŀ		40	μА			4.5V			l
Reset (8202, 8203)			40	μΑ				4.5V		1
Input Voltage Rating			1							
(All inputs)	5.5			v	10mA	10mA	10mA	10mA		
Power/Current Consumption		409/77.7	580/110	mW/mA	0V	0V	ov	100		11,13

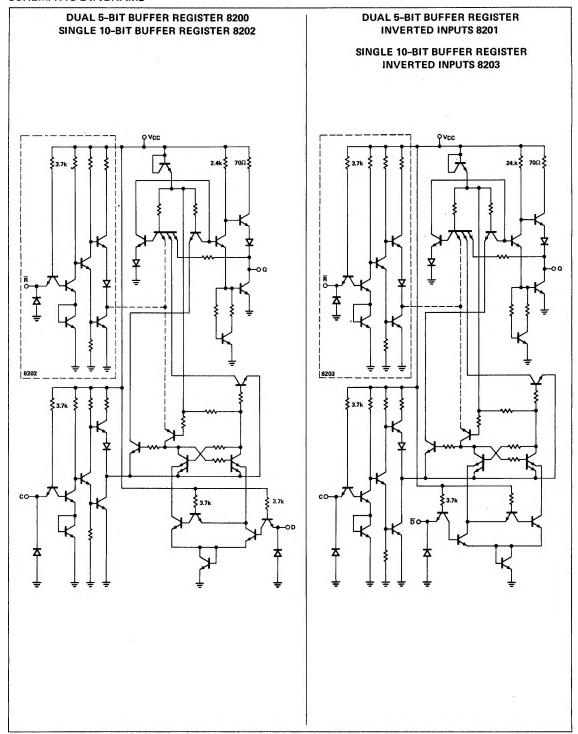
$T_A = 25^{\circ}C$ and $V_{CC} = 5.0V$

	LIMITS				######################################	
CHARACTERISTICS	MIN.	MIN. TYP, MAX.		UNITS	TEST CONDITIONS	NOTES
Propagation Delay	:					
ton Clock to Q		30	45	ns		8
toff Clock to Q		25	40	ns		8
ton Reset to Q		30	45	ns		8
Set Up Time		6	15	ns		10
Hold Time		0	` 5	ns		12
Minimum Clock Pulse Width		12	17	ns		[
Transfer Rate	15	35		MHz		8
Output Short Circuit Current	-20		-70	mA		9, 13

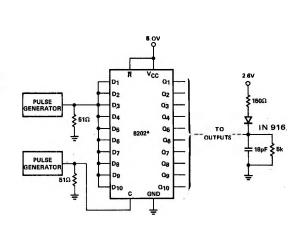
NOTES:

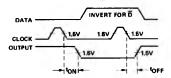
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are tied to V_{CC}.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition:
- "UP" Level = "1", "DOWN" Level = "0 ".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation diodes become forward biased.
- Output source current is supplied through a resistor to 6. ground.
- Output sink current is supplied through a resistor to V_{CC}.
- Refer to AC Test Figure. R.
- 9. Not more than one output should be shorted at a time.
- Set Up Time defined as data presence before clock. 10.
- 11. Outputs are in the low state for this test.
- Hold time defined as data presence after clock. 12.
- 13. V_{CC} = 5.25 volts.

SCHEMATIC DIAGRAMS



AC TEST FIGURES AND WAVEFORMS



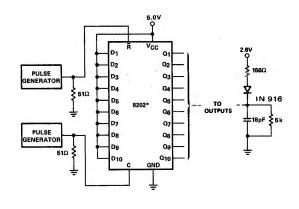


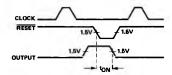
INPUT PULSE: Date = P.R.R. = 7.5 MHz Clock = P.R.R. = 15 MHz PW = 17 ns (at 50% point) $t_r = t_f = 5$ ns Mex. Amplitude = 2.6V.

*Refer to the Pin-Outs for the 8200/01/03 AC Testing.

tpd FROM CLOCK TO Q

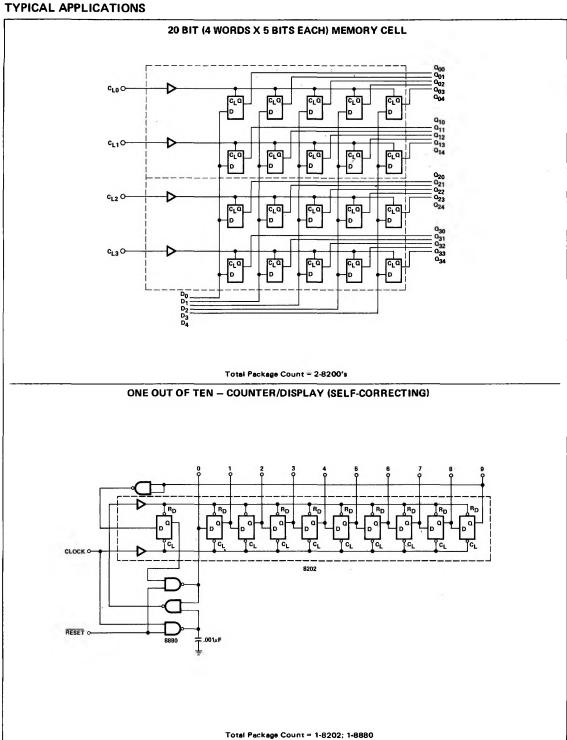
ton FROM RESET TO Q





INPUT PULSE: Amplitude = 2.6V Clock: P.R.R. = 5 MHz Reset: P.R.R. = 5 MHz PW = 30 ns (at 50% point) t_r = t_f = 5 ns

*Refer to the Pin-Outs for the 8200/01/02/03 AC Testing.



TYPICAL APPLICATIONS (Cont'd)

